

SGW15N60RUF

Short Circuit Rated IGBT

General Description

Fairchild's RUF series of Insulated Gate Bipolar Transistors (IGBTs) provide low conduction and switching losses as well as short circuit ruggedness. The RUF series is designed for applications such as motor control, uninterrupted power supplies (UPS) and general inverters where short circuit ruggedness is a required feature.

Features

- Short circuit rated 10us @ $T_C = 100$ °C, $V_{GE} = 15$ V
- High speed switching
- Low saturation voltage : $V_{CE(sat)} = 2.2 \text{ V} @ I_C = 15 \text{A}$
- High input impedance

Applications

AC & DC motor controls, general purpose inverters, robotics, and servo controls.





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Description	190.19	SGW15N60RUF	Units
V _{CES}	Collector-Emitter Voltage	GN//0 -	600	V
V _{GES}	Gate-Emitter Voltage	L West	± 20	V
I _C	Collector Current	$@ T_C = 25^{\circ}C$	24	А
	Collector Current	@ T _C = 100°C	15	Α
I _{CM (1)}	Pulsed Collector Current		45	Α
T _{SC}	Short Circuit Withstand Time	@ T _C = 100°C	10	us
PD	Maximum Power Dissipation	$@ T_C = 25^{\circ}C$	160	W
	Maximum Power Dissipation	@ T _C = 100°C	64	W
TJ	Operating Junction Temperature		-55 to +150	°C
T _{stg}	Storage Temperature Range		-55 to +150	°C
T _L	Maximum Lead Temp. for Soldering Purposes, 1/8" from Case for 5 Seconds		300	°C

Notes:
(1) Repetitive rating: Pulse width limited by max. junction temperature

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.77	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (PCB Mount) (2)		40	°C/W

(2) Mounted on 1" squre PCB (FR4 or G-10 Material)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Off Chai	racteristics					
BV _{CES}	Collector-Emitter Breakdown Voltage	$V_{GE} = 0V, I_{C} = 250uA$	600			V
$\Delta B_{VCES}/$ ΔT_J	Temperature Coefficient of Breakdown Voltage	V _{GE} = 0V, I _C = 1mA		0.6		V/°C
I _{CES}	Collector Cut-Off Current	$V_{CE} = V_{CES}, V_{GE} = 0V$			250	uA
I _{GES}	G-E Leakage Current	$V_{GE} = V_{GES}, V_{CE} = 0V$			± 100	nA
On Char	acteristics					
V _{GE(th)}	G-E Threshold Voltage	I _C = 15mA, V _{CE} = V _{GE}	5.0	6.0	8.5	V
· GE(th)	Collector to Emitter	$I_C = 15A$, $V_{GE} = 15V$		2.2	2.8	V
$V_{CE(sat)}$	Saturation Voltage	$I_C = 24A$, $V_{GF} = 15V$		2.5		V
	c Characteristics	-				
C _{ies}	Input Capacitance	$V_{CE} = 30V_{V_{GE}} = 0V_{V_{CE}}$		948		pF
C _{oes}	Output Capacitance	f = 1MHz		101		pF
C _{res}	Reverse Transfer Capacitance	1 – 11011 12		33		pF
t _{d(on)} t _r	Turn-On Delay Time Rise Time			17 33		ns ns
	· ·	-				
t _{d(off)}	Turn-Off Delay Time	$V_{CC} = 300 \text{ V}, I_{C} = 15\text{A},$		44	65	ns
t _f	Fall Time	$R_G = 13\Omega, V_{GE} = 15V,$		118	200	ns
E _{on}	Turn-On Switching Loss	Inductive Load, $T_C = 25^{\circ}C$		320		uJ
⊏ _{on} E _{off}	Turn-Off Switching Loss			356		uJ
Ε _{ts}	Total Switching Loss	-		676	950	uJ
t _{d(on)}	Turn-On Delay Time			20		ns
t _r	Rise Time	-		34		ns
	Turn-Off Delay Time	$V_{CC} = 300 \text{ V}, I_{C} = 15\text{A},$		48	70	ns
t _{d(off)} t _f	Fall Time	$R_G = 13\Omega, V_{GE} = 15V,$		212	350	ns
E _{on}	Turn-On Switching Loss	Inductive Load, T _C = 125°C		340		uJ
E _{off}	Turn-Off Switching Loss	1		695		uJ
E _{ts}	Total Switching Loss	-		1035	1450	uJ
T _{sc}	Short Circuit Withstand Time	V _{CC} = 300 V, V _{GE} = 15V @ T _C = 100°C	10			us
Q _g	Total Gate Charge			42	60	nC
Q _{ge}	Gate-Emitter Charge	$V_{CE} = 300 \text{ V, } I_{C} = 15 \text{A,}$		7	10	nC
		$V_{GF} = 15V$	1	1		
Q _{gc}	Gate-Collector Charge	VGE = 13V		17	24	nC

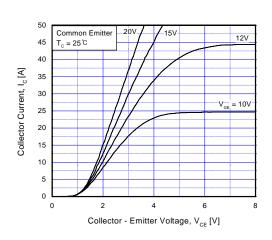
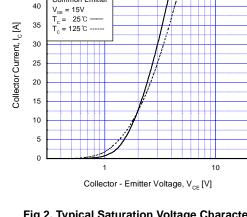


Fig 1. Typical Output Characteristics



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Fig 2. Typical Saturation Voltage Characteristics

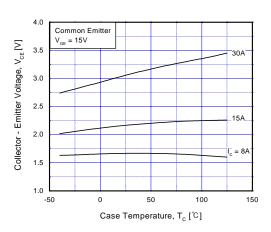


Fig 3. Saturation Voltage vs. Case **Temperature at Variant Current Level**

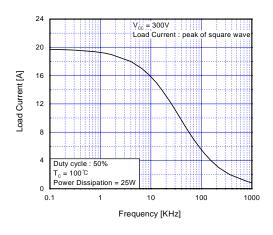


Fig 4. Load Current vs. Frequency

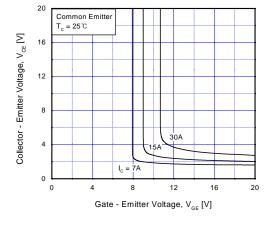


Fig 5. Saturation Voltage vs. V_{GE}

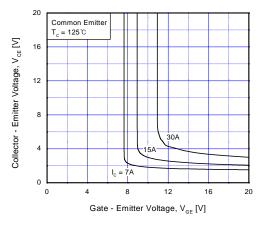
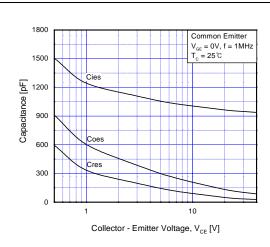


Fig 6. Saturation Voltage vs. V_{GE}

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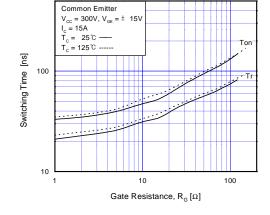
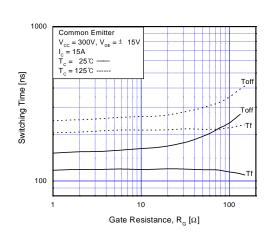


Fig 7. Capacitance Characteristics

Fig 8. Turn-On Characteristics vs.
Gate Resistance



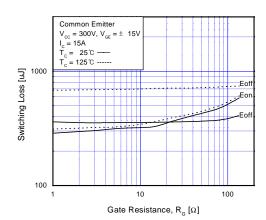
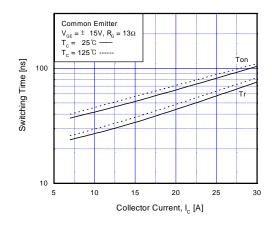


Fig 9. Turn-Off Characteristics vs.
Gate Resistance

Fig 10. Switching Loss vs. Gate Resistance



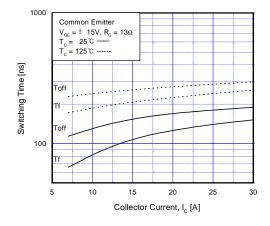
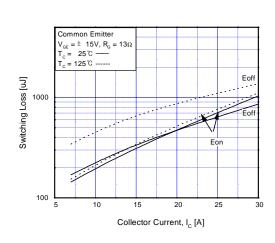


Fig 11. Turn-On Characteristics vs. Collector Current

Fig 12. Turn-Off Characteristics vs. Collector Current



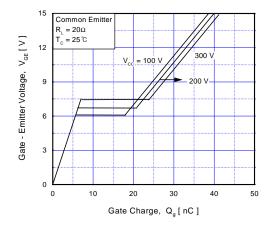
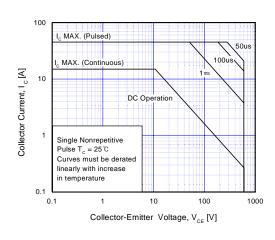


Fig 13. Switching Loss vs. Collector Current

Fig 14. Gate Charge Characteristics



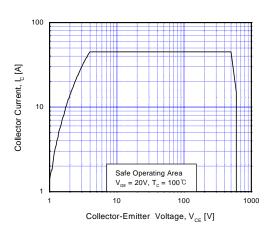


Fig 15. SOA Characteristics

Fig 16. Turn-Off SOA Characteristics

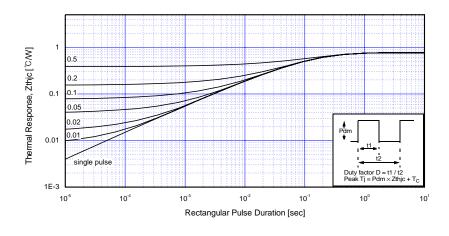
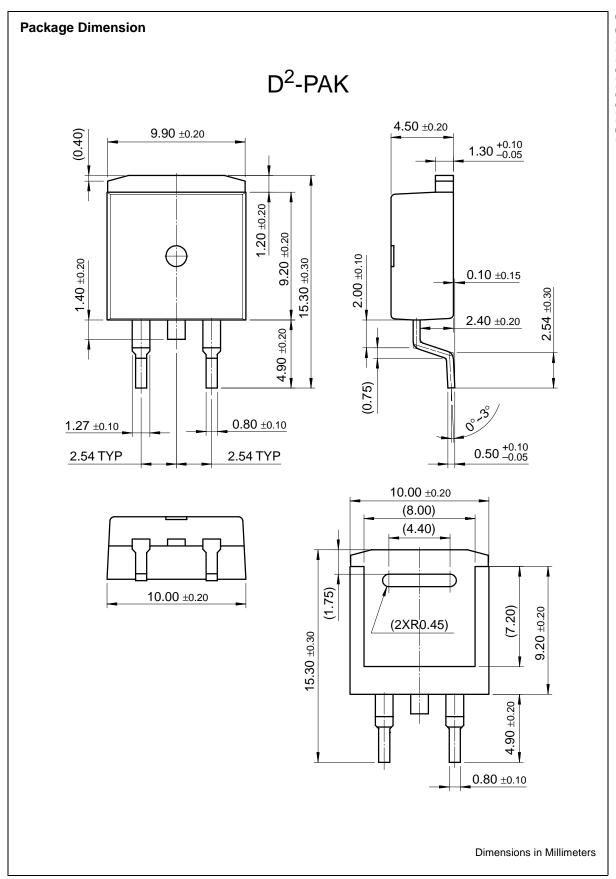


Fig 17. Transient Thermal Impedance of IGBT

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